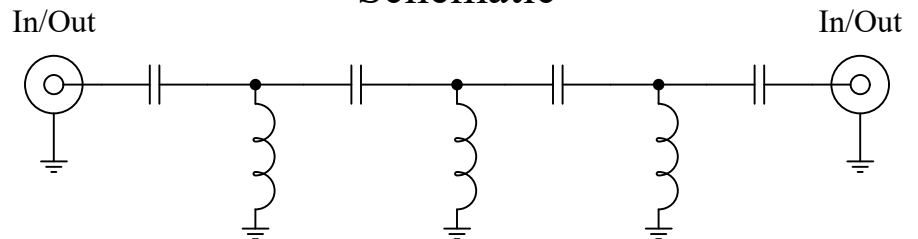


High Pass Filter
50Ω SMA
700 MHz 7th Order
Part Number: CHPFL-0700



Schematic



Features:

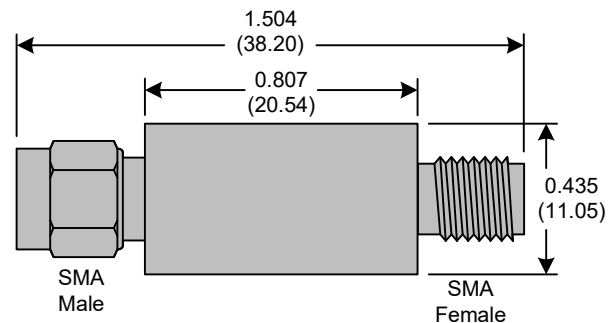
- 7th Order Butterworth Response
- 50Ω SMA Connectors

Applications:

- Test Equipment
- Lab Use

Maximum Ratings:

- +36dBm (4 Watts)
- Operating Temperature: -40°C to 85°C
- Storage Temperature: -55°C to 100°C



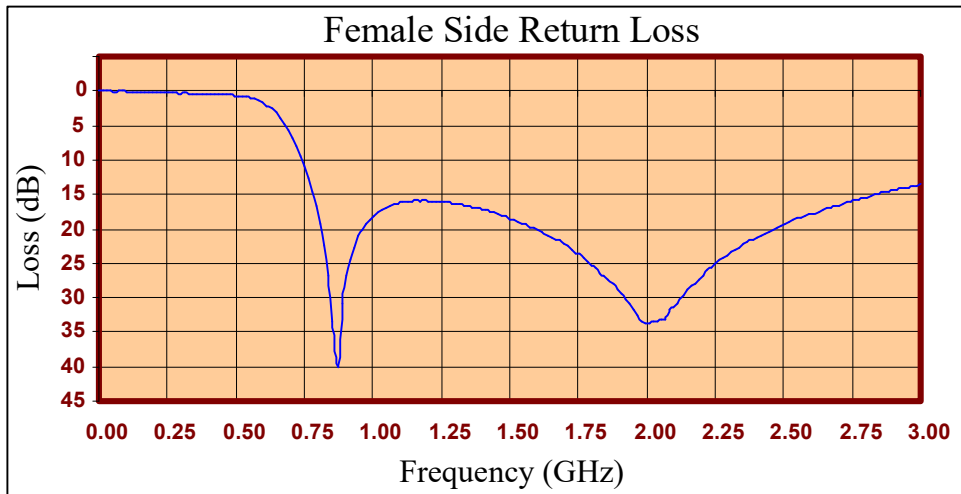
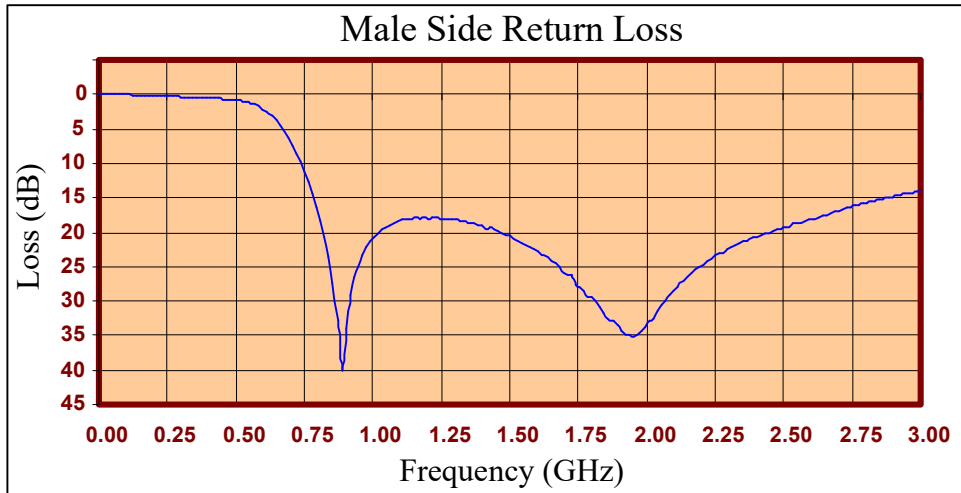
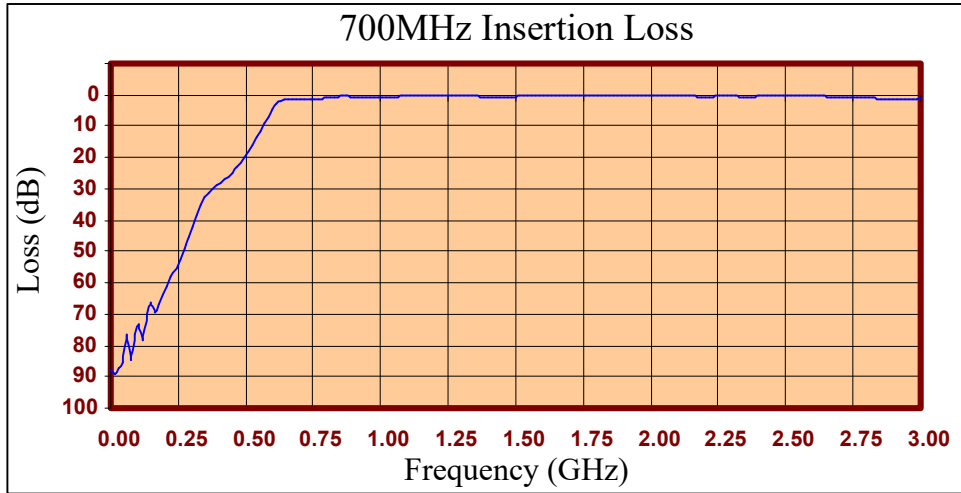
Crystek's line of High Pass Filters are designed in a rugged SMA housing. This filter line has excellent out-of-band rejection. Designed for Test Equipment and General Lab Use.

Product Control:

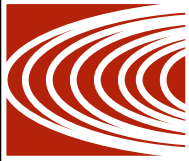
Crystek Part Number:	CHPFL-0700	Release Date:	13-Apr-2026
Revision Level:	F	Responsible:	K. Piotrowicz



High Pass Filter
 50Ω SMA
 700 MHz 7th Order



Product Control:			
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High Pass Filter
 50Ω SMA
 700 MHz 7th Order

FREQ (MHz)	INSERTION LOSS (dB)	Male Return Loss (dB)	Female Return Loss (dB)
0.3	97.86	0.00	0.00
15.3	94.86	0.01	0.00
30.3	97.85	0.02	0.01
45.3	98.42	0.01	0.01
60.3	109.08	0.04	0.06
75.3	90.12	0.04	0.05
90.3	82.42	0.02	0.05
105	76.80	0.04	0.07
120	71.84	0.08	0.11
135	70.98	0.10	0.13
150	70.14	0.13	0.18
165	69.15	0.17	0.21
180	66.11	0.18	0.25
195	62.28	0.19	0.23
210	58.25	0.18	0.22
225	53.89	0.18	0.23
240	51.56	0.22	0.29
255	51.29	0.24	0.28
270	50.57	0.24	0.33
285	48.70	0.29	0.33
300	45.78	0.36	0.35
330	37.26	0.40	0.39
405	29.33	0.56	0.48
450	18.94	0.70	0.53
510	16.53	0.92	0.71
585	7.57	1.71	1.30
705	2.42	7.31	6.88
810	0.74	18.28	19.36
900	0.59	33.99	26.91
1005	0.63	20.65	18.06
1245	0.57	18.02	16.09
1500	0.46	20.53	18.56
1755	0.21	27.83	23.73
1995	0.27	33.87	33.63
2250	0.69	23.40	24.99
2505	0.50	19.31	19.25
2745	0.62	16.38	16.00
3000	0.80	14.07	13.53

Product Control:

Crystek Part Number:	CHPFL-0700	Release Date:	13-Apr-2026
Revision Level:	F	Responsible:	K. Piotrowicz

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